Search Notes

Application/Control I	No. Applicar Reexam	nt(s)/Patent under ination
10/576,769	HIKAWA	A ET AL.
Examiner	Art Unit	
Rita Leykin	2837	

SEARCHED					
Class	Subclass	Date	Examiner		
318	471	5/25/2007	R.L.		
	806				
	490				
361	29				
	28				
	23				

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
318	471	5/25/2007	R.L.		
	806				
	490				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
USPAT, DERWENT, EPO, JPO, USPGPUB	5/25/2007	R.L.		
EAST	5/25/2007	R.L.		
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